

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/752,644	KEDIA ET AL.	
Examiner	Art Unit	
Tse Chen	2116	

SEARCHED						
Class	Subclass	Date	Examiner			
,						
,						
			*			
		·				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
-					
	ļ				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
text sends only see search pe prewe		7SE	
		·	